

MBN1200E25C

Silicon N-channel IGBT

FEATURES

- * High thermal fatigue durability.
($\Delta T_c=70^\circ\text{C}$, $N>30,000$ cycles)
- * Low noise due to ultra soft fast recovery diode.
- * High speed, low loss IGBT module.
- * Low driving power due to low input capacitance MOS gate.
- * High reliability, high durability module.
- * Isolated head sink (terminal to base).

ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$)

| Item | Symbol | Unit | MBN1200E25C |
|---------------------------|-------------------|------------------|--------------------|
| Collector Emitter Voltage | V_{CES} | V | 2,500 |
| Gate Emitter Voltage | V_{GES} | V | ± 20 |
| Collector Current | DC | I_C | 1,200 |
| | 1ms | I_{cp} | 2,400 |
| Forward Current | DC | I_F | 1,200 |
| | 1ms | I_{FM} | 2,400 |
| Junction Temperature | T_j | $^\circ\text{C}$ | -40 ~ +125 |
| Storage Temperature | T_{stg} | $^\circ\text{C}$ | -40 ~ +125 |
| Isolation Voltage | V_{ISO} | V_{RMS} | 4,000(AC 1 minute) |
| Screw Torque | Terminals (M4/M8) | - | 2/10 (1) |
| | Mounting (M6) | - | 6 (2) |

Notes: (1) Recommended Value $1.8\pm 0.2/9\pm 1\text{N}\cdot\text{m}$ (2) Recommended Value $5.5\pm 0.5\text{N}\cdot\text{m}$

ELECTRICAL CHARACTERISTICS ($T_c=25^\circ\text{C}$)

| Item | Symbol | Unit | Min. | Typ. | Max. | Test Conditions |
|--------------------------------------|-----------------|---------------|------|-------|--------|--|
| Collector Emitter Cut-Off Current | I_{CES} | mA | - | - | 12 | $V_{CE}=2,500\text{V}$, $V_{GE}=0\text{V}$, $T_j=25^\circ\text{C}$ |
| | | | - | 20 | 60 | $V_{CE}=2,500\text{V}$, $V_{GE}=0\text{V}$, $T_j=125^\circ\text{C}$ |
| Gate Emitter Leakage Current | I_{GES} | nA | -500 | - | +500 | $V_{GE}=\pm 20\text{V}$, $V_{CE}=0\text{V}$, $T_j=25^\circ\text{C}$ |
| Collector Emitter Saturation Voltage | $V_{CE(sat)}$ | V | - | 3.0 | 3.5 | $I_C=1,200\text{A}$, $V_{GE}=15\text{V}$, $T_j=125^\circ\text{C}$ |
| Gate Emitter Threshold Voltage | $V_{GE(TH)}$ | V | 4.0 | 5.0 | 6.0 | $V_{CE}=15\text{V}$, $I_C=120\text{mA}$, $T_j=25^\circ\text{C}$ |
| Input Capacitance | C_{ies} | nF | - | 175 | - | $V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_j=25^\circ\text{C}$ |
| Internal Gate Resistance | R_{ge} | Ω | - | 2.2 | - | $V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_j=25^\circ\text{C}$ |
| Switching Times | Rise Time | t_r | - | 3.2 | 4.4 | $V_{CC}=1,000\text{V}$, $I_C=1,200\text{A}$ |
| | Turn On Time | t_{on} | - | 4.2 | 5.2 | $L=100\text{nH}$ |
| | Fall Time | t_f | - | 1.9 | 3.4 | $R_G(\text{ON/OFF})=6.8/1.5\Omega$ (3) |
| | Turn Off Time | t_{off} | - | 3.4 | 5.6 | $V_{GE}=\pm 15\text{V}$, $T_j=125^\circ\text{C}$ |
| Peak Forward Voltage Drop | V_{FM} | V | - | 2.0 | 2.5 | $I_F=1,200\text{A}$, $V_{GE}=0\text{V}$, $T_j=125^\circ\text{C}$ |
| Reverse Recovery Time | t_{rr} | μs | - | 0.9 | 1.4 | $V_{CC}=1,000\text{V}$, $I_F=1,200\text{A}$, $L=100\text{nH}$ $T_j=125^\circ\text{C}$ |
| Turn On Loss | $E_{on(10\%)}$ | J/P | - | 1.8 | 2.3 | $V_{CC}=1,000\text{V}$, $I_C=1,200\text{A}$, $L=100\text{nH}$ |
| Turn Off Loss | $E_{off(10\%)}$ | J/P | - | 1.2 | 1.7 | $R_G(\text{ON/OFF})=6.8/1.5\Omega$ (3) |
| Reverse Recovery Loss | $E_{rr(10\%)}$ | J/P | - | 0.35 | 0.85 | $V_{GE}=\pm 15\text{V}$, $T_j=125^\circ\text{C}$ |
| Stray inductance module | L_{SCE} | nH | - | 12 | - | |
| Thermal Impedance | IGBT | $R_{th(j-c)}$ | - | - | 0.0085 | Junction to case |
| | FWD | $R_{th(j-c)}$ | - | - | 0.017 | |
| Contact Thermal Impedance | $R_{th(c-f)}$ | K/W | - | 0.006 | - | Case to fin |

Notes : (3) R_G value is the test condition's value for evaluation of the switching times, not recommended value.Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.Counter arm IGBT $V_{GE}=-15\text{V}$

- * Please contact our representatives at order.
- * For improvement, specifications are subject to change without notice.
- * For actual application, please confirm this spec sheet is the newest revision.

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DEFINITION OF TEST CIRCUIT

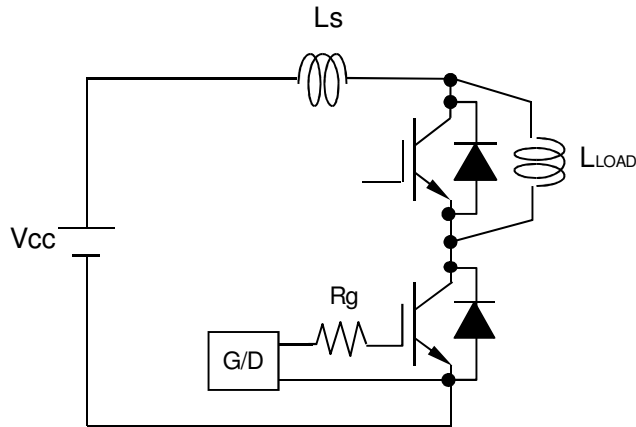


Fig.1 Switching test circuit

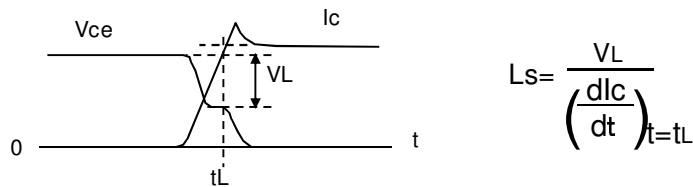


Fig.2 Definition of Ls

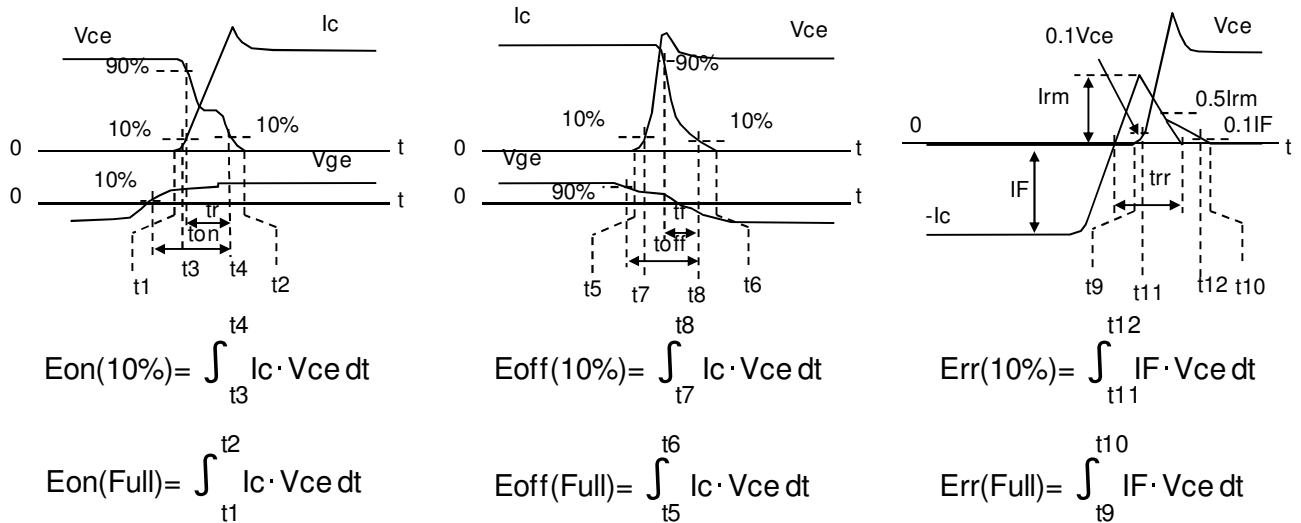
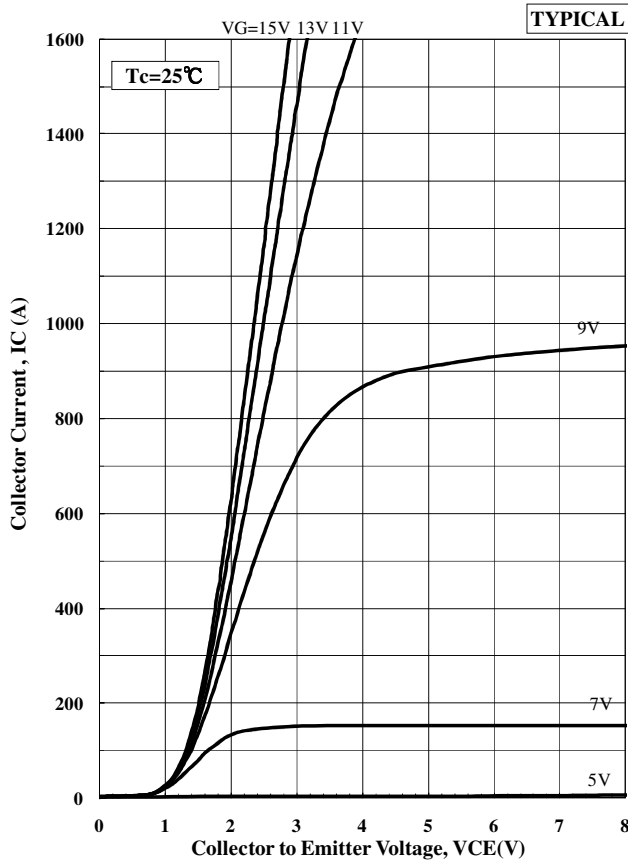


Fig.3 Definition of switching loss

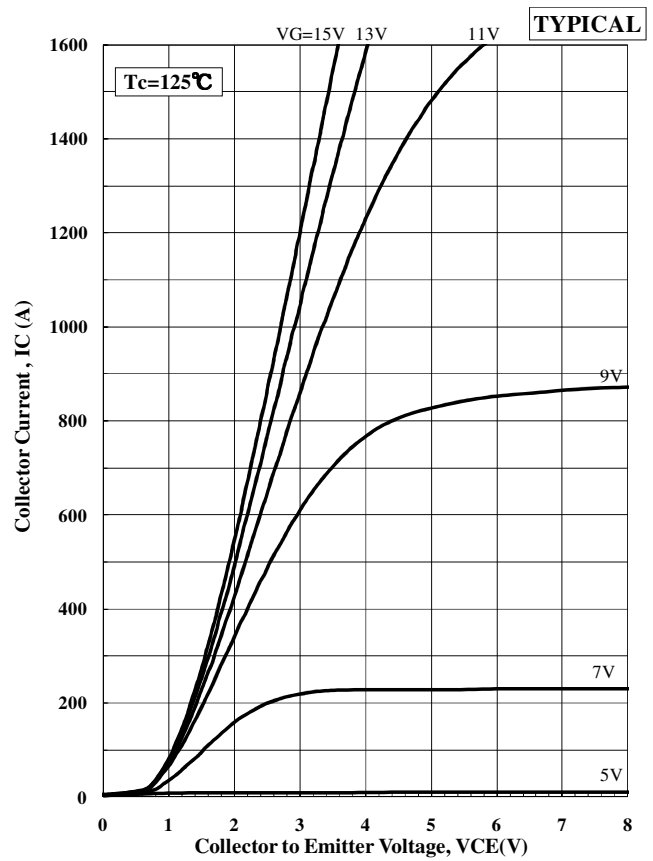
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CHARACTERISTICS CURVE

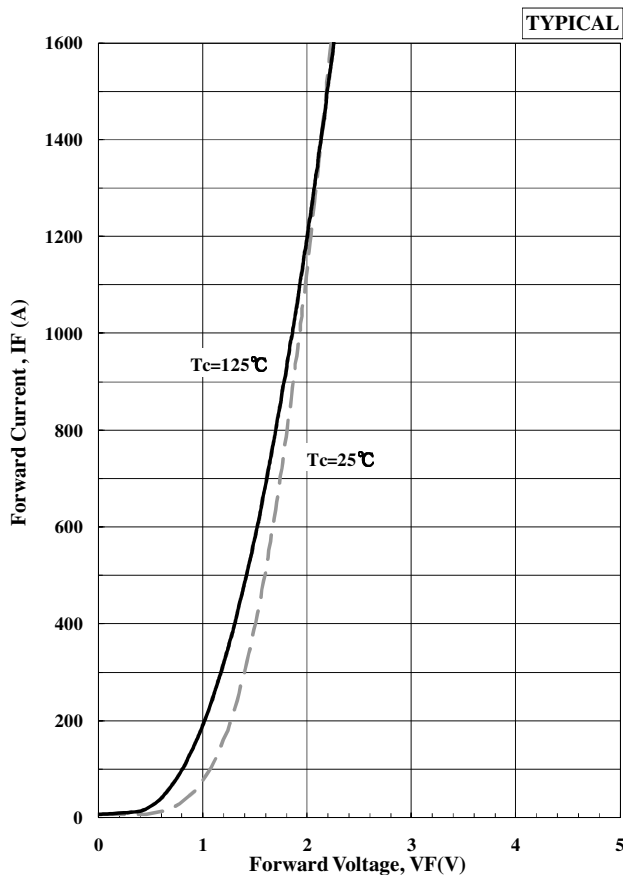
STATIC CHARACTERISTICS



Collector Current vs. Collector to Emitter Voltage



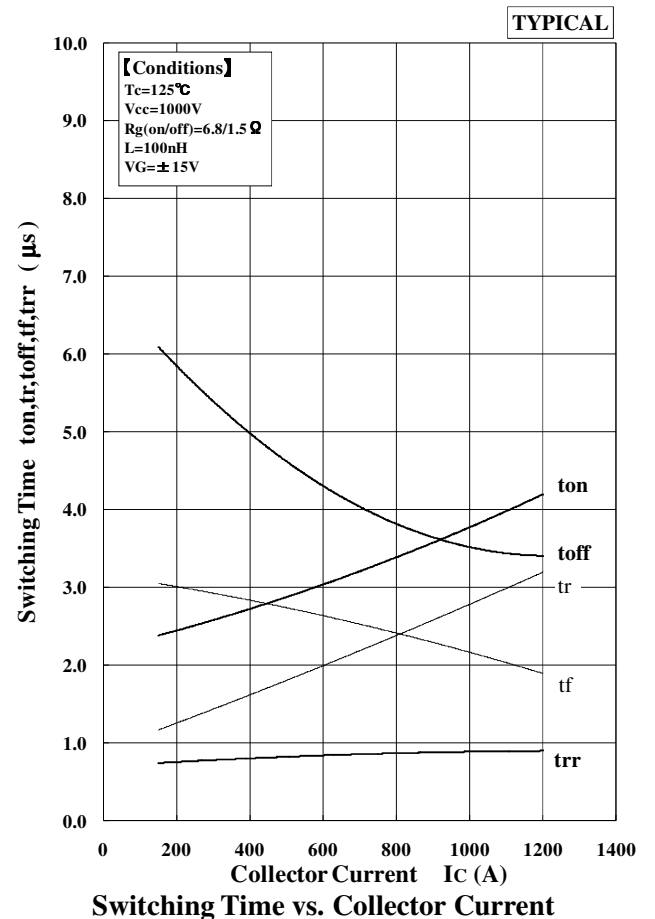
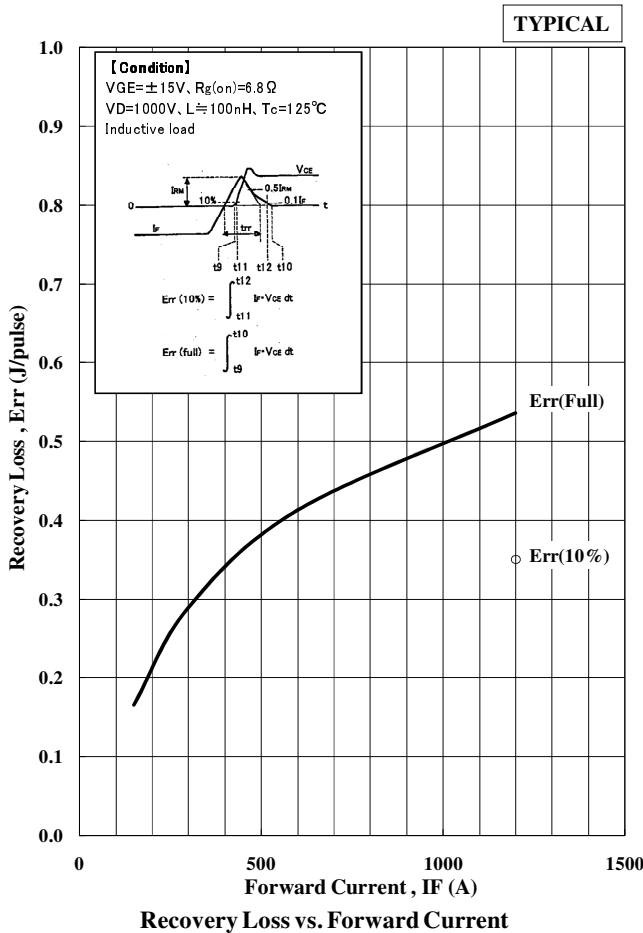
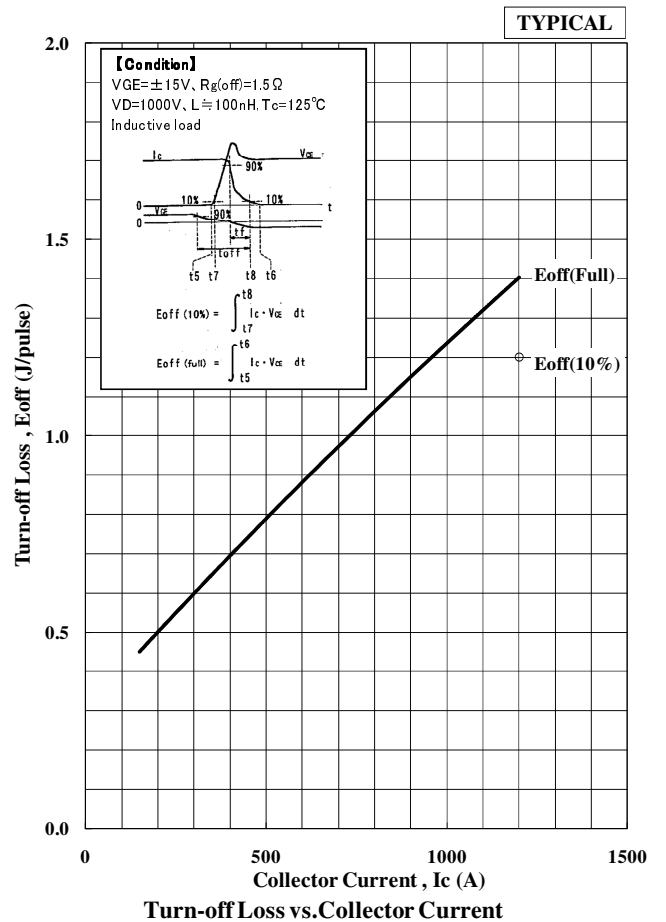
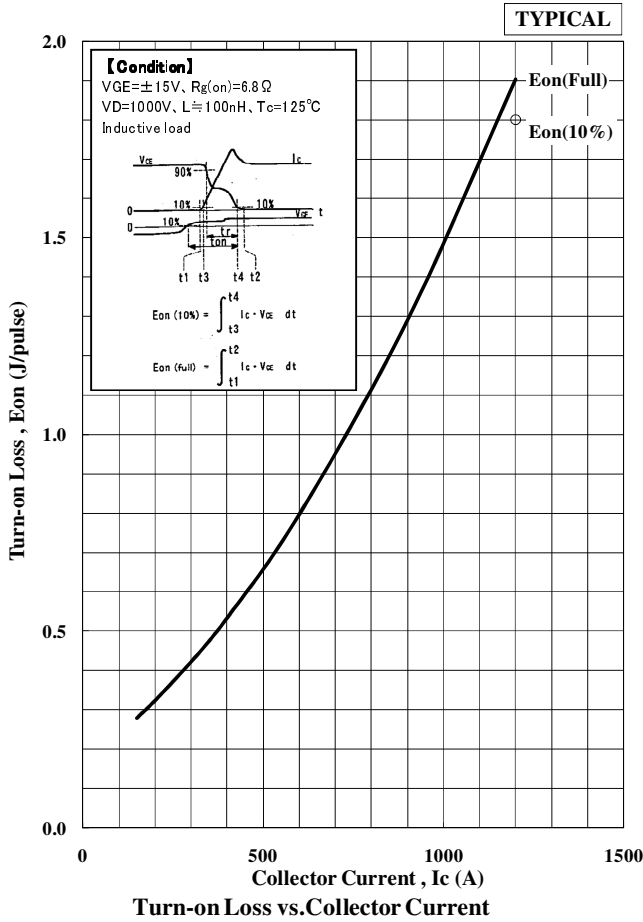
Collector Current vs. Collector to Emitter Voltage



Forward Voltage of free-wheeling diode

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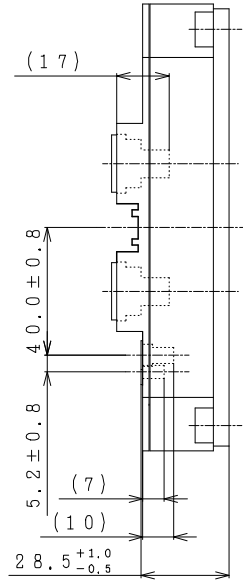
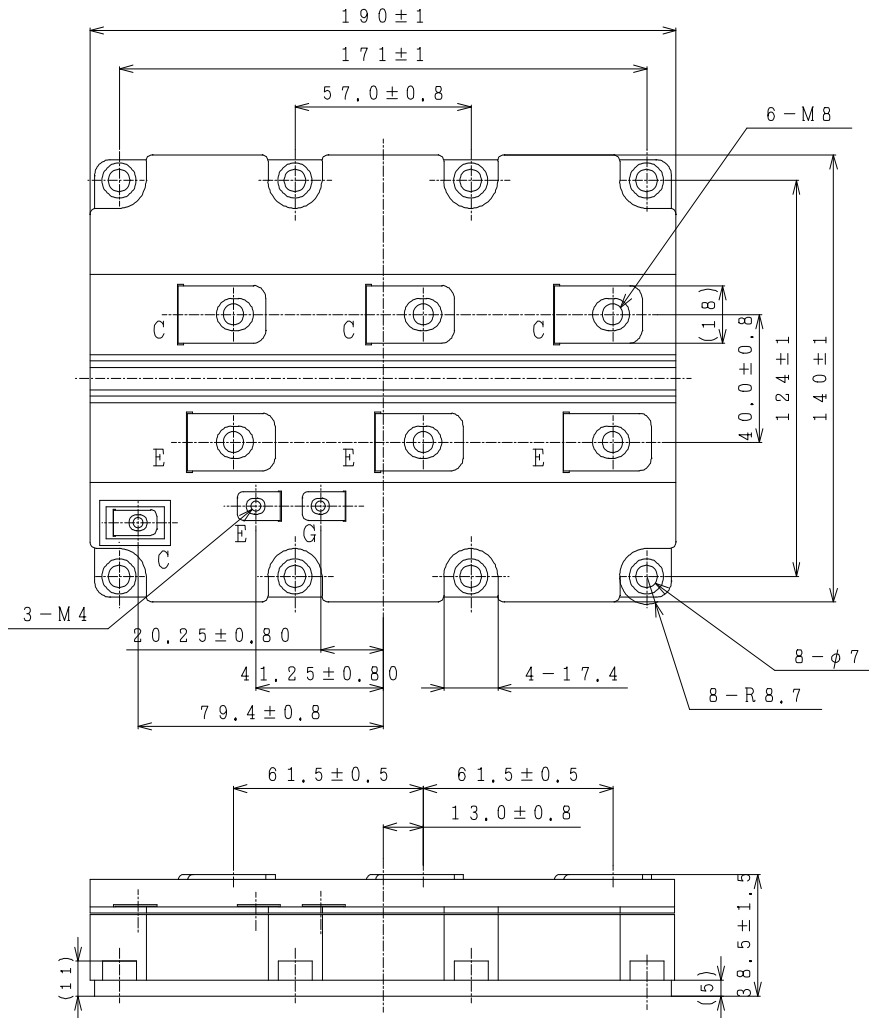
DYNAMIC CHARACTERISTICS



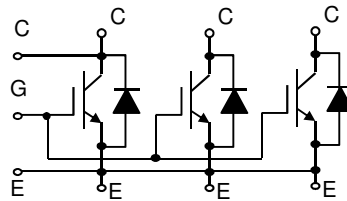
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PACKAGE OUTLINE DRAWING

Unit in mm



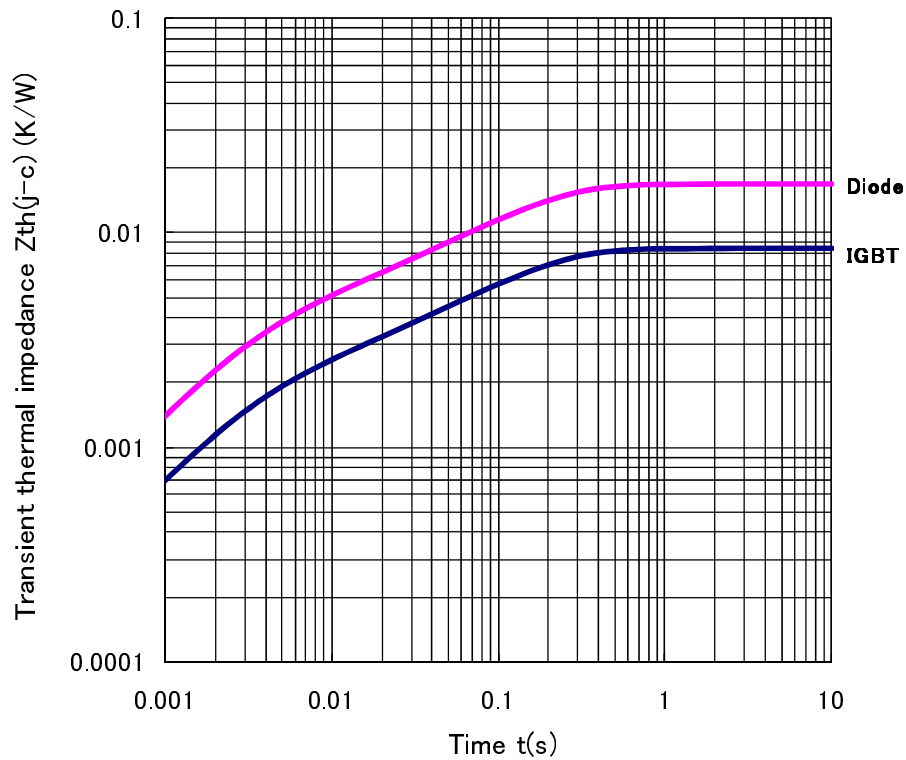
Weight: 1300(g)



Circuit diagram

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TRANSIENT THERMAL IMPEDANCE



Transient Thermal Impedance Curve (Maximum Value)

Material Declaration

Please note that following materials are contained in the product In order to keep characteristics and reliability level.

| Material | Contained part |
|-----------------------------|----------------|
| Lead (Pb) and its compounds | Solder |

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HITACHI POWER SEMICONDUCTORS

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